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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded - Microcontrollers</u>"

| Details | |
|----------------------------|---|
| Product Status | Obsolete |
| Core Processor | RL78 |
| Core Size | 16-Bit |
| Speed | 24MHz |
| Connectivity | CSI, I ² C, LINbus, UART/USART |
| Peripherals | DMA, LCD, LVD, POR, PWM, WDT |
| Number of I/O | 20 |
| Program Memory Size | 16KB (16K x 8) |
| Program Memory Type | FLASH |
| EEPROM Size | 2K x 8 |
| RAM Size | 1K x 8 |
| Voltage - Supply (Vcc/Vdd) | 1.6V ~ 5.5V |
| Data Converters | A/D 4x8/10b |
| Oscillator Type | Internal |
| Operating Temperature | -40°C ~ 85°C (TA) |
| Mounting Type | Surface Mount |
| Package / Case | 32-LQFP |
| Supplier Device Package | 32-LQFP (7x7) |
| Purchase URL | https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f10rbaafp-x0 |

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RL78/L12 1. OUTLINE

| Pin count | Package | Fields of | Part Number |
|-----------|----------------------------------|------------------|---------------------------------------|
| | | Application Note | |
| 32 pins | 32-pin plastic LQFP (7 × 7) | А | R5F10RB8AFP, R5F10RBAAFP, R5F10RBCAFP |
| | | G | R5F10RB8GFP, R5F10RBAGFP, R5F10RBCGFP |
| 44 pins | 44-pin plastic LQFP (10 × 10) | А | R5F10RF8AFP, R5F10RFAAFP, R5F10RFCAFP |
| | | G | R5F10RF8GFP, R5F10RFAGFP, R5F10RFCGFP |
| 48 pins | 48-pin plastic LQFP (fine pitch) | А | R5F10RG8AFB, R5F10RGAAFB, R5F10RGCAFB |
| · | (7 × 7) | G | R5F10RG8GFB, R5F10RGAGFB, R5F10RGCGFB |
| 52 pins | 52-pin plastic LQFP (10 × 10) | А | R5F10RJ8AFA, R5F10RJAAFA, R5F10RJCAFA |
| | | G | R5F10RJ8GFA, R5F10RJAGFA, R5F10RJCGFA |
| 64 pins | 64-pin plastic WQFN (8 × 8) | А | R5F10RLAANB, R5F10RLCANB |
| | | G | R5F10RLAGNB, R5F10RLCGNB |
| | 64-pin plastic LQFP (fine pitch) | Α | R5F10RLAAFB, R5F10RLCAFB |
| | (10 × 10) | G | R5F10RLAGFB, R5F10RLCGFB |
| | 64-pin plastic LQFP (12 × 12) | А | R5F10RLAAFA, R5F10RLCAFA |
| | | G | R5F10RLAGFA, R5F10RLCGFA |

Note For the fields of application, refer to Figure 1-1 Part Number, Memory Size, and Package of RL78/L12.

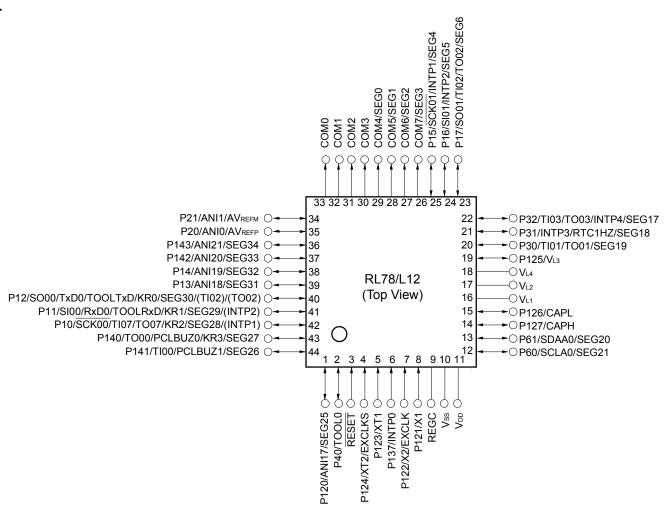
Caution The ordering part numbers represent the numbers at the time of publication. For the latest ordering part numbers, refer to the target product page of the Renesas Electronics website.

RL78/L12 1. OUTLINE

1.3.2 44-pin products

• 44-pin plastic LQFP (10 × 10)

<R>



Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F).

Remarks 1. For pin identification, see 1.4 Pin Identification.

2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

(Ta = -40 to +85°C, 1.6 V \leq EV_{DD} = V_{DD} \leq 5.5 V, Vss = EVss = 0 V)

(3/5)

| Items | Symbol | Conditions | | MIN. | TYP. | MAX. | Unit |
|------------------------|--|--|--|---------------------|---------------------|---------------------|------|
| Input voltage, high | P10 to P17, P30 to P32, P40 to P43, Normal input buffer P50 to P54, P70 to P74, P120, P125 to P127, P140 to P147 | | Normal input buffer | 0.8EV _{DD} | | EV _{DD} | V |
| | V _{IH2} | P10, P11, P15, P16 | TTL input buffer 4.0 V ≤ EV _{DD} ≤ 5.5 V | 2.2 | | EV _{DD} | V |
| | | | TTL input buffer 3.3 V ≤ EV _{DD} < 4.0 V | 2.0 | | EV _{DD} | V |
| | | | TTL input buffer 1.6 V ≤ EV _{DD} < 3.3 V | 1.50 | | EV _{DD} | V |
| V _{IH3} | | P20, P21 | 0.7V _{DD} | | V _{DD} | V | |
| | V _{IH4} P60, P61 | | | 0.7EV _{DD} | | EV _{DD} | V |
| | V _{IH5} | P121 to P124, P137, EXCLK, EXCLK | S, RESET | 0.8V _{DD} | | V _{DD} | V |
| Input voltage, low | VIL1 | P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P140 to P147 | 0 | | 0.2EV _{DD} | V | |
| | V _{IL2} | P10, P11, P15, P16 | TTL input buffer 4.0 V ≤ EV _{DD} ≤ 5.5 V | 0 | | 0.8 | V |
| | | | TTL input buffer 3.3 V ≤ EV _{DD} < 4.0 V | 0 | | 0.5 | V |
| | | | TTL input buffer 1.6 V ≤ EV _{DD} < 3.3 V | 0 | | 0.32 | V |
| | V _{IL3} | P20, P21 | | 0 | | 0.3V _{DD} | V |
| | V _{IL4} | P60, P61 | | 0 | | 0.3EV _{DD} | V |
| | V _{IL5} | P121 to P124, P137, EXCLK, EXCLK | S, RESET | 0 | | 0.2V _{DD} | V |

Caution The maximum value of VIH of P10, P12, P15, P17 is EVDD, even in the N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

2.4 AC Characteristics

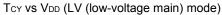
2.4.1 Basic operation

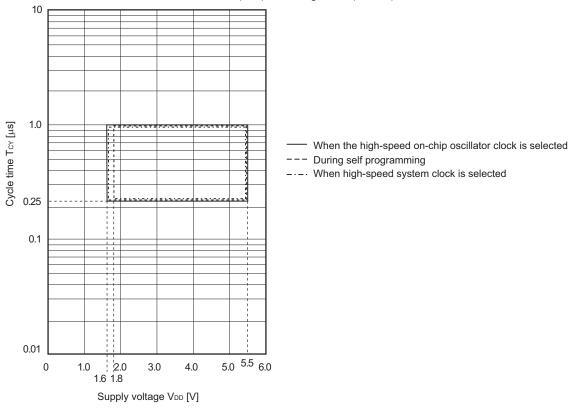
 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$

| Items | Symbol | 0.0 - | Condition | ons | | MIN. | TYP. | MAX. | Unit |
|--|-----------------|---------------------------------|----------------------------|-------|--|-----------|------|------|------|
| Instruction cycle (minimum | Tcy | Main | HS (high-sp | peed | 2.7 V ≤ V _{DD} ≤ 5.5 V | 0.04167 | | 1 | μs |
| instruction execution time) | | system | main) mode | | 2.4 V≤V _{DD} < 2.7 V | | | 1 | μs |
| | | clock (fmain) operation | LV (low volt | | 1.6 V≤V _{DD} ≤5.5 V | 0.25 | | 1 | μs |
| | | | LS (low-spe | | 1.8 V ≤ V _{DD} ≤ 5.5 V | 0.125 | | 1 | μs |
| | | Subsystem operation | clock (fsua) | | 1.8 V≤V _{DD} ≤5.5 V | 28.5 | 30.5 | 31.3 | μs |
| | | In the self . | HS (high-sp | | $2.7 \text{V} \le \text{V}_{\text{DD}} \le 5.5 \text{V}$ | 0.04167 | | 1 | μs |
| | | programmin g mode | , | 9 | $2.4 \text{ V} \le \text{V}_{DD} < 2.7 \text{ V}$ | 0.0625 | | 1 | μs |
| | | 3 | LV (low volt main) mode | | 1.8 V ≤ V _{DD} ≤ 5.5 V | 0.25 | | 1 | μS |
| | | | LS (low-spe main) mode | | 1.8 V ≤ V _{DD} ≤ 5.5 V | 0.125 | | 1 | μs |
| External main system clock | fex | $2.7~V \leq V_{DD}$ | ≤ 5.5 V | | | 1.0 | | 20.0 | MHz |
| frequency | | 2.4 V ≤ V _{DD} | < 2.7 V | | | 1.0 | | 16.0 | MHz |
| | | 1.8 V ≤ V _{DD} | < 2.4 V | | | 1.0 | | 8.0 | MHz |
| | | 1.6 V ≤ V _{DD} < 1.8 V | | | | 1.0 | | 4.0 | MHz |
| | fexs | | | | | 32 | | 35 | kHz |
| External main system clock input | texh, texl | $2.7~V \le V_{DD} \le 5.5~V$ | | | | 24 | | | ns |
| high-level width, low-level width | | 2.4 V ≤ V _{DD} | < 2.7 V | | | 30 | | | ns |
| | | 1.8 V ≤ V _{DD} | < 2.4 V | | | 60 | | | ns |
| | | 1.6 V ≤ V _{DD} | < 1.8 V | | | 120 | | | ns |
| | texhs, texhs | | | | | 13.7 | | | μs |
| TI00 to TI07 input high-level width, low-level width | tтін, tтіL | | | | | 1/fмск+10 | | | ns |
| TO00 to TO07 output frequency | f то | HS (high-sp | |) V ≤ | EV _{DD} ≤ 5.5 V | | | 16 | MHz |
| | | main) mode | 2.7 | 7 V ≤ | EV _{DD} < 4.0 V | | | 8 | MHz |
| | | | 2.4 | 4 V ≤ | EV _{DD} < 2.7 V | | | 4 | MHz |
| | | LS (low-spe main) mode | | 8 V ≤ | EV _{DD} ≤ 5.5 V | | | 4 | MHz |
| | | LV (low volt main) mode | | 6 V ≤ | EVDD ≤ 5.5 V | | | 2 | MHz |
| PCLBUZ0, PCLBUZ1 output | f PCL | HS (high-sp | |) V ≤ | $EV_{DD} \le 5.5 V$ | | | 16 | MHz |
| frequency | | main) mode | 2.7 | 7 V ≤ | EV _{DD} < 4.0 V | | | 8 | MHz |
| | | | | | EV _{DD} < 2.7 V | | | 4 | MHz |
| | | LS (low-spe main) mode | : | 8 V ≤ | ≦ EV _{DD} ≤ 5.5 V | | | 4 | MHz |
| | | LV (low-volt | | | $EV_{DD} \leq 5.5 V$ | | | 4 | MHz |
| | | main) mode | 1.0 | | EV _{DD} < 1.8 V | | | 2 | MHz |
| Interrupt input high-level width, low-level width | tinth, | INTP0 | | | V _{DD} ≤ 5.5 V | 1 | | | μs |
| | tintl | INTP1 to IN | | | EV _{DD} ≤ 5.5 V | 1 | | | μs |
| Key interrupt input low-level width | t kr | KR0 to KR3 | | | EV _{DD} ≤ 5.5 V | 250 | | | ns |
| DECET lave laved with | 4 | | 1.6 | o V ≤ | EV _{DD} < 1.8 V | 1 | | | μs |
| RESET low-level width | t RSL | | | | | 10 | | | μS |

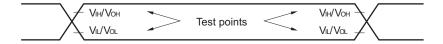
Remark fmck: Timer array unit operation clock frequency

(Operation clock to be set by the CKS0n bit of timer mode register 0n (TMR0n). n: Channel number (n = 0 to 7))

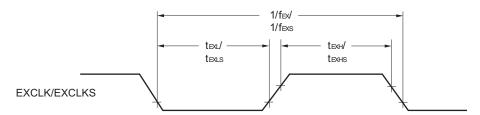




AC Timing Test Points

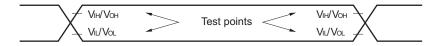


External System Clock Timing



2.5 Peripheral Functions Characteristics

AC Timing Test Points



2.5.1 Serial array unit

(1) During communication at same potential (UART mode)

(Ta = -40 to +85°C, 1.6 V \leq EV_{DD} = V_{DD} \leq 5.5 V, Vss = EVss = 0 V)

| Parameter | Symbol | Conditions | | ` ` | h-speed Mode | ` | /-speed Mode | · ` | -voltage Mode | Unit |
|----------------------|--------|------------|---|------|-----------------|------|-----------------|------|------------------|------|
| | | | | MIN. | MAX. | MIN. | MAX. | MIN. | MAX. | |
| Transfer rate Note 1 | | 2.4 \ | / ≤ EV _{DD} = V _{DD} ≤ 5.5 V | | fмск/6 | | fмск/6 | | fмск/6 | bps |
| | | | Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 2}$ | | 4.0 | | 1.3 | | 0.6 | Mbps |
| | | 1.8 \ | / ≤ EV _{DD} = V _{DD} ≤ 5.5 V | | | | fмск/6 | | fмск/6 | bps |
| | | | Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 2}$ | | | | 1.3 | | 0.6 | Mbps |
| | | 1.6 \ | / ≤ EV _{DD} = V _{DD} ≤ 5.5 V | | | | | | fмск/6 | bps |
| | | | Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 2}$ | | | | | | 0.6 | Mbps |

Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.

2. The maximum operating frequencies of the CPU/peripheral hardware clock (fclk) are:

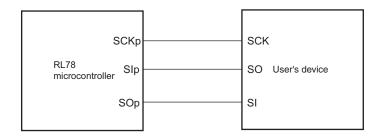
HS (high-speed main) mode: 24 MHz (2.7 V \leq VDD \leq 5.5 V)

16 MHz (2.4 V \leq V_{DD} \leq 5.5 V)

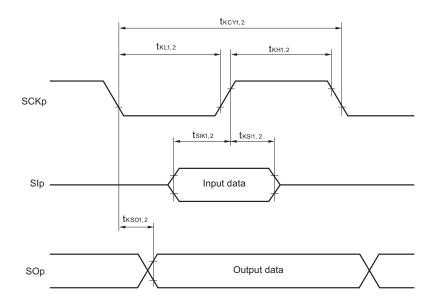
LS (low-speed main) mode: 8 MHz (1.8 V \leq VDD \leq 5.5 V) LV (low-voltage main) mode: 4 MHz (1.6 V \leq VDD \leq 5.5 V)

Caution Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

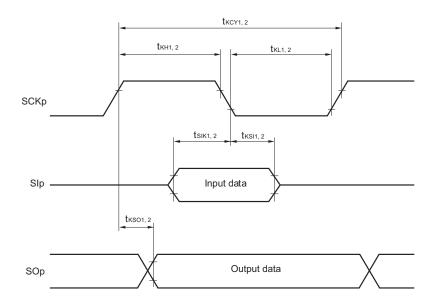
CSI mode connection diagram (during communication at same potential)



CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



Remarks 1. p: CSI number (p = 00, 01)

2. m: Unit number, n: Channel number (mn = 00, 01)

(6) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output) (3/3) (T_A = −40 to +85°C, 1.8 V ≤ EV_{DD} = V_{DD} ≤ 5.5 V, V_{SS} = EV_{SS} = 0 V)

| Parameter | Symbol | Conditions | | high- | | (low- | | (low- | Unit |
|--|-------------------|--|------|--------------|------|--------------|------|----------------|------|
| | | | • | main) ode | | main) ode | | e main) ode | |
| | | | | 1 | | | | | |
| | | | MIN. | MAX. | MIN. | MAX. | MIN. | MAX. | |
| SIp hold time (from SCKp↓) Note 2 | t _{KSI1} | $ \begin{array}{l} 4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V, \\ C_b = 30 \ pF, \ R_b = 1.4 \ k\Omega \end{array} $ | 19 | | 19 | | 19 | | ns |
| | | $ \begin{array}{l} 2.7 \; V \leq EV_{DD} < 4.0 \; V, \; 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array} $ | 19 | | 19 | | 19 | | ns |
| | | $ \begin{array}{l} 2.4 \; V \leq EV_{DD} < 3.3 \; V, 1.6 \; V \leq V_b \leq 2.0 \; V, \\ C_b = 30 \; pF, \; R_b = 5.5 \; k\Omega \end{array} $ | 19 | | 19 | | 19 | | ns |
| | | $ \begin{array}{l} 1.8 \ V \leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V \leq V_b \leq 2.0 \ V^{\text{Note 3}}, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array} $ | | | 19 | | 19 | | ns |
| Delay time from SCKp↑ to SOp output Note 2 | tkso1 | $ \begin{array}{l} 4.0 \; V \leq EV_{DD} \leq 5.5 \; V, 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 30 \; pF, \; R_b = 1.4 \; k\Omega \end{array} $ | | 25 | | 25 | | 25 | ns |
| | | $ \begin{array}{c} 2.7 \; V \leq EV_{DD} < 4.0 \; V, 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array} $ | | 25 | | 25 | | 25 | ns |
| | | $ \begin{array}{c} 2.4 \; V \leq EV_{DD} < 3.3 \; V, 1.6 \; V \leq V_b \leq 2.0 \; V, \\ C_b = 30 \; pF, \; R_b = 5.5 \; k\Omega \end{array} $ | | 25 | | 25 | | 25 | ns |
| | | $\begin{array}{l} 1.8 \ V \leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V \leq V_b \leq 2.0 \ V^{\text{Note 3}}, \\ C_b = 30 \ \text{pF}, \ R_b = 5.5 \ \text{k}\Omega \end{array}$ | | | | 25 | | 25 | ns |

Notes

- 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
- 2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 3. Use it with $EV_{DD} \ge V_b$.

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (32-pin to 52-pin products)/EVDD tolerance (64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

2.6 Analog Characteristics

2.6.1 A/D converter characteristics

Classification of A/D converter characteristics

| | Reference Voltage | | | | | | | |
|--|--|--|--|--|--|--|--|--|
| Input channel | Reference voltage (+) = AVREFP Reference voltage (-) = AVREFM | Reference voltage (+) = V _{DD} Reference voltage (-) = Vss | Reference voltage (+) = VBGR Reference voltage (-) = AVREFM | | | | | |
| ANIO, ANI1 | _ | Refer to 2.6.1 (3). | Refer to 2.6.1 (4). | | | | | |
| ANI16 to ANI23 | Refer to 2.6.1 (2). | | | | | | | |
| Internal reference voltage Temperature sensor output voltage | Refer to 2.6.1 (1) . | | _ | | | | | |

(1) When reference voltage (+) = AVREFP/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin : internal reference voltage, and temperature sensor output voltage

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, 1.6 \text{ V} \le \text{AV}_{REFP} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V}, \text{Reference voltage (+)} = \text{AV}_{REFP}, \text{Reference voltage (-)} = \text{AV}_{REFM} = 0 \text{ V})$

| Parameter | Symbol | Condit | tions | MIN. | TYP. | MAX. | Unit |
|--|-------------------|--|---|-------------------------|----------------------------|-------|------|
| Resolution | RES | | | 8 | | 10 | bit |
| Overall error ^{Note 1} | AINL | 10-bit resolution | $1.8~V \leq V_{DD} \leq 5.5~V$ | | 1.2 | ±3.5 | LSB |
| | | AV _{REFP} = V _{DD} Note 3 | $1.6~V \leq V_{DD} \leq 5.5~V^{\text{Note 4}}$ | | 1.2 | ±7.0 | LSB |
| Conversion time | tconv | 10-bit resolution | $3.6~V \leq V_{DD} \leq 5.5~V$ | 2.375 | | 39 | μs |
| | | Target pin: Internal reference | $2.7~V \leq V_{DD} \leq 5.5~V$ | 3.5625 | | 39 | μs |
| | | voltage, and temperature sensor output voltage (HS (high-speed main) mode) | 2.4 V ≤ V _{DD} ≤ 5.5 V | 17 | | 39 | μs |
| Zero-scale error ^{Notes 1, 2} E _{ZS} | 10-bit resolution | 1.8 V ≤ AV _{REFP} ≤ 5.5 V | | | ±0.25 | %FSR | |
| | | AV _{REFP} = V _{DD} Note 3 | 1.6 V ≤ AV _{REFP} ≤ 5.5 V Note 4 | | | ±0.50 | %FSR |
| Full-scale error Notes 1, 2 | E _{FS} | 10-bit resolution | 1.8 V ≤ AV _{REFP} ≤ 5.5 V | | | ±0.25 | %FSR |
| | | AV _{REFP} = V _{DD} Note 3 | $1.6 \text{ V} \le \text{AV}_{\text{REFP}} \le 5.5 \text{ V}^{\text{Note 4}}$ | | | ±0.50 | %FSR |
| Integral linearity | ILE | 10-bit resolution | $1.8~V \leq V_{DD} \leq 5.5~V$ | | | ±2.5 | LSB |
| error ^{Note 1} | | AV _{REFP} = V _{DD} Note 3 | $1.6~V \leq V_{DD} \leq 5.5~V^{\text{Note 4}}$ | | | ±5.0 | LSB |
| Differential linearity | DLE | 10-bit resolution | $1.8~V \leq V_{DD} \leq 5.5~V$ | | | ±1.5 | LSB |
| error ^{Note 1} | | AV _{REFP} = V _{DD} Note 3 | $1.6~V \leq V_{DD} \leq 5.5~V^{\text{Note 4}}$ | | | ±2.0 | LSB |
| Analog input voltage | VAIN | Internal reference voltage (2.4 V \leq V _{DD} \leq 5.5 V, HS (high- | | V _{BGR} Note 5 | | V | |
| | V _B GR | Temperature sensor output vo $(2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, HS (high-$ | O . | | V _{TMPS25} Note 5 | | V |

Notes 1. Excludes quantization error ($\pm 1/2$ LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. When AVREFP < VDD. the MAX, values are as follows.

Overall error: Add ± 1.0 LSB to the MAX. value when AV_{REFP} = V_{DD}.

Zero-scale error/Full-scale error: Add ±0.05%FSR to the MAX. value when AVREFP = VDD.

Integral linearity error/Differential linearity error: Add ± 0.5 LSB to the MAX. value when AV_{REFP} = V_{DD}.

- **4.** Values when the conversion time is set to 57 μ s (min.) and 95 μ s (max.).
- 5. Refer to 2.6.2 Temperature sensor/internal reference voltage characteristics.

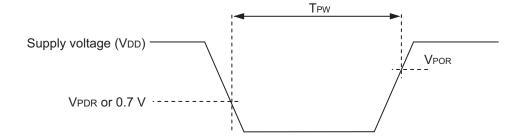


2.6.3 POR circuit characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$

| Parameter | Symbol | Conditions | MIN. | TYP. | MAX. | Unit |
|-------------------------------------|------------------|------------------------|------|------|------|------|
| Detection voltage | VPOR | Power supply rise time | | 1.51 | 1.55 | V |
| | V _{PDR} | Power supply fall time | 1.46 | 1.50 | 1.54 | V |
| Minimum pulse width ^{Note} | Tpw | | 300 | | | μs |

Note Minimum time required for a POR reset when V_{DD} exceeds below V_{PDR}. This is also the minimum time required for a POR reset from when V_{DD} exceeds below 0.7 V to when V_{DD} exceeds V_{POR} while STOP mode is entered or the main system clock is stopped through setting bit 0 (HIOSTOP) and bit 7 (MSTOP) in the clock operation status control register (CSC).



3. ELECTRICAL SPECIFICATIONS (G: $T_A = -40 \text{ to } +105^{\circ}\text{C}$)

This chapter describes the electrical specifications for the products "G: Industrial applications ($T_A = -40$ to +105°C)".

- Cautions 1. The RL78 microcontrollers have an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.
 - 2. With products not provided with an EVDD or EVss pin, replace EVDD with VDD, or replace EVss with Vss
 - 3. For derating with $T_A = +85$ to +105°C, contact our Sales Division or the vender's sales division. Derating means the specified reduction in an operating parameter to improve reliability.

(4) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode) $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS} = 0 \text{ V})$

(2/2)

| Parameter | Symbol | | Condit | ions | HS (high-spee | ed main) Mode | Unit |
|---------------|--------|-----------------------------------|---|--|---------------|----------------|------|
| | | | | | MIN. | MAX. | |
| Transfer rate | | Transmission | $4.0 \text{ V} \leq \text{EV}_{DD} \leq 5.5 \text{ V},$ | | | Note 1 | bps |
| | | | $2.7~V \leq V_b \leq 4.0~V$ | Theoretical value of the maximum transfer rate $C_b = 50 \text{ pF}, R_b = 1.4 \text{ k}\Omega, V_b = 2.7 \text{ V}$ | | 2.0 Note 2 | Mbps |
| | | | 2.7 V ≤ EV _{DD} < 4.0 V, | | | Note 3 | bps |
| | | | $2.3~V \leq V_b \leq 2.7~V$ | Theoretical value of the maximum transfer rate $C_b = 50 \text{ pF}, R_b = 2.7 \text{ k}\Omega, V_b = 2.3 \text{ V}$ | | 1.2 Note 4 | Mbps |
| | | 2.4 V ≤ EV _{DD} < 3.3 V, | | | Note 5 | bps | |
| | | | $1.6~V \leq V_b \leq 2.0~V$ | Theoretical value of the maximum transfer rate $C_b = 50 \text{ pF}, R_b = 5.5 \text{ k}\Omega, V_b = 1.6 \text{ V}$ | | 0.43 Note 6 | Mbps |

Notes 1. The smaller maximum transfer rate derived by using fmck/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 4.0 V \leq EV_{DD} \leq 5.5 V and 2.7 V \leq V_b \leq 4.0 V

Maximum transfer rate =
$$\frac{1}{\{-C_b \times R_b \times ln (1 - \frac{2.2}{V_b})\} \times 3} [bps]$$

Baud rate error (theoretical value) =
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln (1 - \frac{2.2}{V_b})\}}{\frac{1}{(\text{Transfer rate})} \times \text{Number of transferred bits}} \times 100 \, [\%]$$

- * This value is the theoretical value of the relative difference between the transmission and reception sides.
- **2.** This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 1 above to calculate the maximum transfer rate under conditions of the customer.
- 3. The smaller maximum transfer rate derived by using fmck/6 or the following expression is the valid maximum transfer rate.

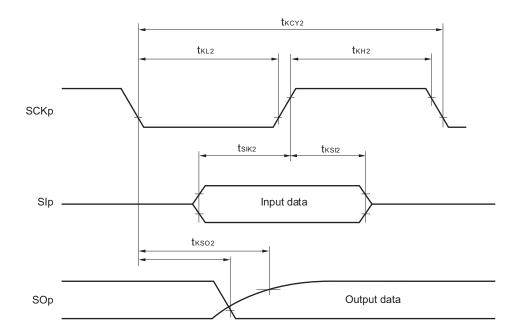
Expression for calculating the transfer rate when 2.7 V \leq EV_{DD} < 4.0 V and 2.3 V \leq V_b \leq 2.7 V

Maximum transfer rate =
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\} \times 3}$$
 [bps]

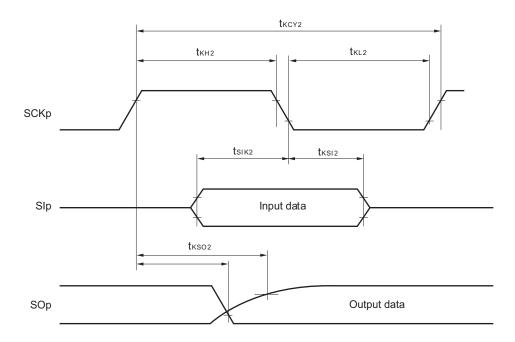
Baud rate error (theoretical value) =
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 \, [\%]$$

- * This value is the theoretical value of the relative difference between the transmission and reception sides.
- **4.** This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 3 above to calculate the maximum transfer rate under conditions of the customer.

CSI mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



CSI mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



Remark p: CSI number (p = 00, 01), m: Unit number (m = 0),

n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)

(2) I²C fast mode

(TA = -40 to +105°C, 2.4 V \leq EVDD = VDD \leq 5.5 V, Vss = EVss = 0 V)

| Parameter | Symbol Conditions | | onditions | HS (high-spe | ed main) Mode | Unit | |
|---|-------------------|---|----------------------------------|---|---------------|------|-----|
| | | | | | MAX. | | |
| SCLA0 clock frequency | fscL | fscl Fast mode: | | $2.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}$ | 0 | 400 | kHz |
| | | fclк≥ 3.5 MHz | 2.4 V ≤ EV _{DD} ≤ 5.5 V | 0 | 400 | | |
| Setup time of restart condition | tsu:sta | $2.7 \text{ V} \leq \text{EV}_{DD} \leq 5.$ | 5 V | 0.6 | | μs | |
| | | $2.4 \text{ V} \leq \text{EV}_{DD} \leq 5.5 \text{ V}$ | | 0.6 | | | |
| Hold time Note 1 | thd:sta | thd:STA $2.7 \text{ V} \leq \text{EV}_{DD} \leq 5.5 \text{ V}$ $2.4 \text{ V} \leq \text{EV}_{DD} \leq 5.5 \text{ V}$ | | 0.6 | | μs | |
| | | | | 0.6 | | | |
| Hold time when SCLA0 = "L" | tLOW | 2.7 V ≤ EV _{DD} ≤ 5.5 V | | 1.3 | | μs | |
| | | $2.4 \text{ V} \leq \text{EV}_{DD} \leq 5.$ | 5 V | 1.3 | | | |
| Hold time when SCLA0 = "H" | t HIGH | HIGH $2.7 \text{ V} \leq \text{EV}_{DD} \leq 5.5 \text{ V}$ | | 0.6 | | μs | |
| | | $2.4 \text{ V} \leq \text{EV}_{DD} \leq 5.$ | 5 V | 0.6 | | | |
| Data setup time (reception) | tsu:dat | $2.7 \text{ V} \leq \text{EV}_{DD} \leq 5.$ | 5 V | 100 | | ns | |
| | | $2.4 \text{ V} \leq \text{EV}_{DD} \leq 5.$ | 5 V | 100 | | | |
| Data hold time (transmission) ^{Note 2} | thd:dat | $2.7 \text{ V} \leq \text{EV}_{DD} \leq 5.$ | 5 V | 0 | 0.9 | μs | |
| | | $2.4 \text{ V} \leq \text{EV}_{DD} \leq 5.$ | 5 V | 0 | 0.9 | | |
| Setup time of stop condition | tsu:sto | $2.7 \text{ V} \leq \text{EV}_{DD} \leq 5.$ | 5 V | 0.6 | | μs | |
| | | 2.4 V ≤ EV _{DD} ≤ 5. | 5 V | 0.6 | |] | |
| Bus-free time | t BUF | $2.7 \text{ V} \leq \text{EV}_{DD} \leq 5.$ | 5 V | 1.3 | | μs | |
| | | 2.4 V ≤ EV _{DD} ≤ 5. | 5 V | 1.3 | | | |

- Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.
 - 2. The maximum value (MAX.) of $t_{HD:DAT}$ is during normal transfer and a wait state is inserted in the \overline{ACK} (acknowledge) timing.

Remark The maximum value of Cb (communication line capacitance) and the value of Rb (communication line pull-up resistor) at that time in each mode are as follows.

Fast mode: $C_b = 320 \text{ pF}, R_b = 1.1 \text{ k}\Omega$

3.6 Analog Characteristics

3.6.1 A/D converter characteristics

Classification of A/D converter characteristics

| Oldssilication of Arb converter characteristics | | | | | | | | | |
|--|--|---|--|--|--|--|--|--|--|
| | | Reference Voltage | | | | | | | |
| | Reference voltage (+) = AV _{REFP} | Reference voltage (+) = V _{DD} | Reference voltage (+) = V _{BGR} | | | | | | |
| Input channel | Reference voltage (–) = AVREFM | Reference voltage (-) = Vss | Reference voltage (–) = AV _{REFM} | | | | | | |
| ANI0, ANI1 | - | Refer to 3.6.1 (3). | Refer to 3.6.1 (4). | | | | | | |
| ANI16 to ANI23 | Refer to 3.6.1 (2). | | | | | | | | |
| Internal reference voltage Temperature sensor output voltage | Refer to 3.6.1 (1) . | | - | | | | | | |

(1) When reference voltage (+) = AVREFP/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin: internal reference voltage, and temperature sensor output voltage

(T_A = -40 to +105°C, 2.4 V ≤ EV_{DD} = V_{DD} ≤ 5.5 V, 2.4 V ≤ AV_{REFP} ≤ V_{DD} ≤ 5.5 V, V_{SS} = EV_{SS} = 0 V, Reference voltage (+) = AVREFP, Reference voltage (-) = AVREFM = 0 V)

| Parameter | Symbol | Conditions | | | TYP. | MAX. | Unit |
|--|--------|---|--|--------|--------------------------|-------|------|
| Resolution | RES | | | 8 | | 10 | bit |
| Overall error ^{Note 1} | AINL | 10-bit resolution AV _{REFP} = V _{DD} Note 3 | 2.4 V ≤ AV _{REFP} ≤ 5.5 V | | 1.2 | ±3.5 | LSB |
| Conversion time | tconv | 10-bit resolution | $3.6 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$ | 2.375 | | 39 | μs |
| | | Target pin: Internal reference | $2.7~V \leq V_{DD} \leq 5.5~V$ | 3.5625 | | 39 | μs |
| | Se | voltage, and temperature sensor output voltage (HS (high-speed main) mode) | $2.4~V \le V_{DD} \le 5.5~V$ | 17 | | 39 | μs |
| Zero-scale error ^{Notes 1, 2} | Ezs | 10-bit resolution AV _{REFP} = V _{DD} Note 3 | 1.8 V ≤ AV _{REFP} ≤ 5.5 V | | | ±0.25 | %FSR |
| Full-scale error ^{Notes 1, 2} | Ers | 10-bit resolution AV _{REFP} = V _{DD} Note 3 | 1.8 V ≤ AV _{REFP} ≤ 5.5 V | | | ±0.25 | %FSR |
| Integral linearity error | ILE | 10-bit resolution AV _{REFP} = V _{DD} Note 3 | 1.8 V ≤ AV _{REFP} ≤ 5.5 V | | | ±2.5 | LSB |
| Differential linearity error | DLE | 10-bit resolution AV _{REFP} = V _{DD} Note 3 | 1.8 V ≤ AV _{REFP} ≤ 5.5 V | | | ±1.5 | LSB |
| Analog input voltage | Vain | Internal reference voltage (2.4 V \leq VDD \leq 5.5 V, HS (high-speed main) mode) Temperature sensor output voltage (2.4 V \leq VDD \leq 5.5 V, HS (high-speed main) mode) | | | V _{BGR} Note 4 | | V |
| | | | | | V _{TMPS25} Note | 4 | V |

Notes 1. Excludes quantization error ($\pm 1/2$ LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. When AVREFP < VDD, the MAX. values are as follows.

Overall error: Add ± 1.0 LSB to the MAX. value when AV_{REFP} = V_{DD}.

Zero-scale error/Full-scale error: Add $\pm 0.05\%$ FSR to the MAX. value when AVREFP = VDD.

Integral linearity error/ Differential linearity error: Add ± 0.5 LSB to the MAX. value when AVREFP = VDD.

4. Refer to 3.6.2 Temperature sensor/internal reference voltage characteristics.



(3) When reference voltage (+) = V_{DD} (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = V_{SS} (ADREFM = 0), target pin : ANI0, ANI1, ANI16 to ANI23, internal reference voltage, and temperature sensor output voltage

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V}, \text{Reference voltage (+)} = \text{V}_{DD}, \text{ Reference voltage (-)} = \text{V}_{SS})$

| Parameter | Symbol | Conditions | | MIN. | TYP. | MAX. | Unit |
|--|--------|---|--|--------------|-------------------------|------------------|------|
| Resolution | RES | | | 8 | | 10 | bit |
| Overall error ^{Note 1} | AINL | 10-bit resolution | $2.4~V \leq V_{DD} \leq 5.5~V$ | | 1.2 | ±7.0 | LSB |
| Conversion time | tconv | 10-bit resolution | $3.6~V \leq V_{DD} \leq 5.5~V$ | 2.125 | | 39 | μs |
| | | | $2.7~V \leq V_{\text{DD}} \leq 5.5~V$ | 3.1875 | | 39 | μs |
| | | | 2.4 V ≤ V _{DD} ≤ 5.5 V | | | 39 | μs |
| | | 10-bit resolution | $3.6~V \leq V_{DD} \leq 5.5~V$ | 2.375 | | 39 | μs |
| | | Target pin: Internal reference | $2.7~V \leq V_{\text{DD}} \leq 5.5~V$ | 3.5625 | | 39 | μs |
| | | voltage, and temperature sensor output voltage (HS (high-speed main) mode) | $2.4~V \le V_{DD} \le 5.5~V$ | 17 | | 39 | μs |
| Zero-scale error ^{Notes 1, 2} | Ezs | 10-bit resolution | $2.4~V \leq V_{DD} \leq 5.5~V$ | | | ±0.60 | %FSR |
| Full-scale error ^{Notes 1, 2} | Ers | 10-bit resolution | $2.4~V \leq V_{DD} \leq 5.5~V$ | | | ±0.60 | %FSR |
| Integral linearity error Note 1 | ILE | 10-bit resolution | 10-bit resolution 2.4 V ≤ V _{DD} ≤ 5.5 V | | | ±4.0 | LSB |
| Differential linearity error | DLE | 10-bit resolution | $2.4~\textrm{V} \leq \textrm{V}_\textrm{DD} \leq 5.5~\textrm{V}$ | | | ±2.0 | LSB |
| Analog input voltage | VAIN | ANI0, ANI1 ANI16 to ANI23 Internal reference voltage output (2.4 $V \le V_{DD} \le 5.5 V$, HS (high-speed main) mode) | | 0 | | V _{DD} | V |
| | | | | 0 | | EV _{DD} | V |
| | | | | | V _{BGR} Note 3 | | V |
| | | Temperature sensor output volt (2.4 V \leq V _{DD} \leq 5.5 V, HS (high-s | \ | VTMPS25 Note | 3 | V | |

Notes 1. Excludes quantization error ($\pm 1/2$ LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. Refer to 3.6.2 Temperature sensor/internal reference voltage characteristics.

3.6.2 Temperature sensor/internal reference voltage characteristics

(TA = -40 to +105°C, 2.4 V \leq EV_{DD} = V_{DD} \leq 5.5 V, Vss = EVss = 0 V, HS (high-speed main) mode)

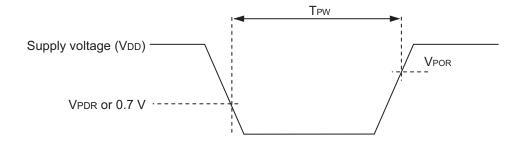
| Parameter | Symbol | Conditions | MIN. | TYP. | MAX. | Unit |
|-----------------------------------|---------------------|--|------|------|------|-------|
| Temperature sensor output voltage | V _{TMPS25} | Setting ADS register = 80H, TA = +25°C | | 1.05 | | V |
| Internal reference voltage | V _{BGR} | Setting ADS register = 81H | 1.38 | 1.45 | 1.5 | ٧ |
| Temperature coefficient | Fvтмps | Temperature sensor that depends on the temperature | | -3.6 | | mV/°C |
| Operation stabilization wait time | tamp | | 5 | | | μs |

3.6.3 POR circuit characteristics

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$

| Parameter | Symbol | Conditions | MIN. | TYP. | MAX. | Unit |
|---------------------|------------------|------------------------|------|------|------|------|
| Detection voltage | V _{POR} | Power supply rise time | 1.45 | 1.51 | 1.57 | V |
| | V _{PDR} | Power supply fall time | 1.44 | 1.50 | 1.56 | V |
| Minimum pulse width | T _{PW} | | 300 | | | μS |

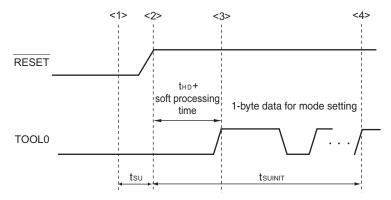
Note Minimum time required for a POR reset when V_{DD} exceeds below V_{PDR}. This is also the minimum time required for a POR reset from when V_{DD} exceeds below 0.7 V to when V_{DD} exceeds V_{POR} while STOP mode is entered or the main system clock is stopped through setting bit 0 (HIOSTOP) and bit 7 (MSTOP) in the clock operation status control register (CSC).



3.11 Timing Specifications for Switching Flash Memory Programming Modes

$(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V})$

| Parameter | Symbol | Conditions | MIN. | TYP. | MAX. | Unit |
|--|-------------|---|------|------|------|------|
| Time to complete the communication for the initial setting after the external reset is released | tsuinit | POR and LVD reset must be released before the external reset is released. | | | 100 | ms |
| Time to release the external reset after the TOOL0 pin is set to the low level | tsu | POR and LVD reset must be released before the external reset is released. | 10 | | | μs |
| Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory) | t HD | POR and LVD reset must be released before the external reset is released. | 1 | | | ms |



- <1> The low level is input to the TOOL0 pin.
- <2> The external reset is released (POR and LVD reset must be released before the external reset is released.).
- <3> The TOOL0 pin is set to the high level.
- <4> Setting of the flash memory programming mode by UART reception and complete the baud rate setting.

Remark tsuinit: Communication for the initial setting must be completed within 100 ms after the external reset is released during this period.

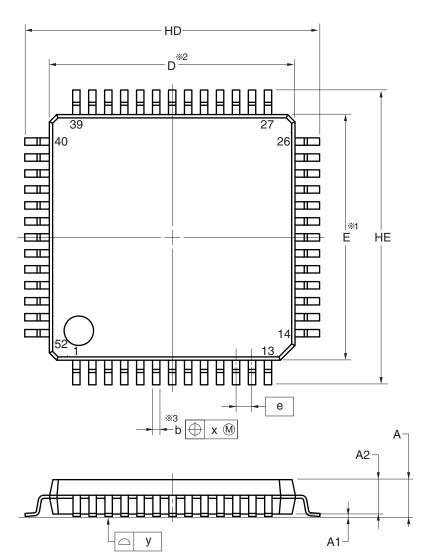
tsu: Time to release the external reset after the TOOL0 pin is set to the low level

Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)

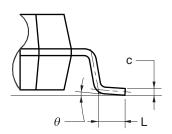
4.4 52-pin Products

R5F10RJ8AFA, R5F10RJAAFA, R5F10RJCAFA R5F10RJ8GFA, R5F10RJAGFA, R5F10RJCGFA

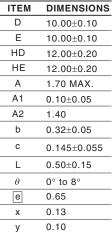
| JEITA Package Code | RENESAS Code | Previous Code | MASS (TYP.) [g] |
|---------------------|--------------|----------------|-----------------|
| P-LQFP52-10x10-0.65 | PLQP0052JA-A | P52GB-65-GBS-1 | 0.3 |



detail of lead end



(UNIT:mm)
IMENSIONS



NOTE 1. Dimensions " % 1" and "% 2" do not include mold flash.

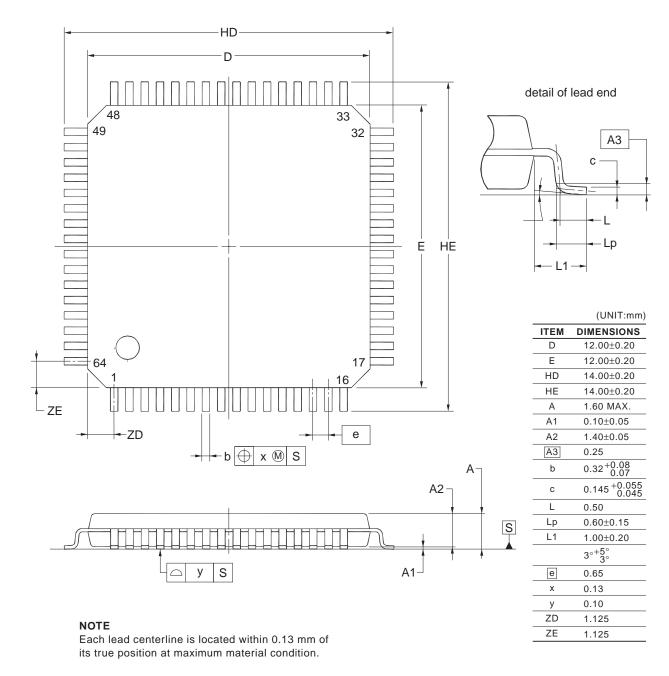
2.Dimension "%3" does not include trim offset.

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4.5 64-pin Products

R5F10RLAAFA, R5F10RLCAFA R5F10RLAGFA, R5F10RLCGFA

| JEITA Package Code | RENESAS Code | Previous Code | MASS (TYP.) [g] |
|---------------------|--------------|----------------|-----------------|
| P-LQFP64-12x12-0.65 | PLQP0064JA-A | P64GK-65-UET-2 | 0.51 |



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